

The activation itself of the redundant rows is done by reading the content of memory address locations 192 and 160. This transfers the repair information stored nonvolatily in the memory array to volatile repair registers.

It is important to note that the repair registers are cleared (bit 5 set to “1”) by any $\text{Reset} = \text{L}$ signal. Thus, any LH transition of the Reset signal must immediately be followed by reading the memory address locations 192 and 160, which restores the repair information to the repair registers.

SR 2 may be substituted by SR 1, whereas SR 1 cannot be substituted. As well, row 0 which contains the memory address locations 192 and 160 cannot be substituted.

SR 1 and SR 2 are part of the memory matrix portion that is not protectable by the \overline{S} signal. Memory address locations 192 and 160 are part of the protectable portion.

1.3. Testing

The MDA 2062 EEPROM contains circuitry designed to facilitate testing of the various functions. By programming data into address location 4, the device is switched to one or more of a number of test modes. A detailed description is given in section 6.

1.4. Protected Matrix

The programming matrix contains a protectable portion. Addresses 128 to 134, 160 to 166, 192 to 198 and 224 to 230 can only be programmed if the “Safe” input \bar{S} (pin 6) is at high potential. In that way, this portion of the memory is protected against inadvertent reprogramming even if such false informations were received via the IM bus. The second part of the programming matrix is not protected.

1.5. Shipment

Parts are shipped with all bits set to “1”, except for addresses 192 and 160 which may contain repair information. The content of memory address locations 192 and 160, if different from 255, should not be altered, as this will result in defective rows appearing within the memory address space.

2. Outline Dimensions and Pin Connections

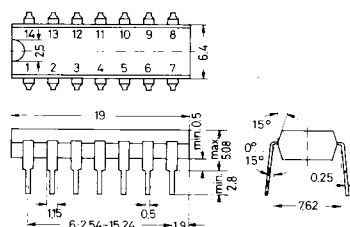


Fig. 3:
MDA 2062 in 14-pin DIL Plastic Package TO-116,
20 A 14 according to DIN 41870

Weight approx. 1.2 g Dimensions in mm

Pin Connctions

- 1 Option Input
- 2 NC
- 3 Programming Voltage V_P
- 4 NC
- 5 NC
- 6 Safe Input \overline{S}
- 7 Ground, 0
- 8 IM Bus Clock Input
- 9 IM Bus Ident Input
- 10 IM Bus Data Input/Output
- 11 NC
- 12 $\overline{\text{Reset}}$ Input
- 13 Memory Clock Input
- 14 Supply Voltage V_{DD}

3. Electrical Characteristics

All voltages are referred to pin 7.

Absolute Maximum Ratings

	Symbol	Value	Unit
Supply Voltage	V_{DD}	− 0.5 to +6	V
Programming Voltage	V_P	$(V_{DD} - 0.8 \text{ V})$ to +22 V	—
V_P Supply Current	I_P	7	mA
Input Voltages	V_I	− 0.3 V to V_{DD}	—
Output Current	I_{10}	5	mA
Ambient Operating Temperature Range	T_A	0 to +65	°C
Storage Temperature Range	T_S	− 40 to +125*	°C

* Stored data may be affected by T_S above +85 °C.

Recommended Operating Conditions

	Symbol	Min.	Typ.	Max.	Unit
Supply Voltage	V_{DD}	4.75	5.0	5.25	V
Programming Voltage when non-programming	V_P	$(V_{DD} - 0.7 \text{ V})$	—	21	V
when programming	V_P	19	20	21	V
Programming Current Limit (see Fig. 4)	I_{Pmax}	—	—	5	mA
Input Voltages Pins 1, 6, 8, 9, 10 and 13	V_{IL}	—	—	0.8	V
	V_{IH}	2.4	—	—	V
Pin 12	V_{IL}	—	—	1.3	V
	V_{IH}	2.4	—	—	V
Memory Clock Frequency	f_{13}	0.9	1.0	1.1	kHz
Memory Clock Input Ratio	R_{13}	0.2	—	99.8	%
V_{DD} Rise Time	t_1	—	—	500	ms
V_P Rise Time	t_2	0.01	—	500	ms
$V_P - V_{DD}$ Delay Time	t_3	—	—	50	ms
$V_{DD} - V_{12}$ Delay Time	t_4	0	—	—	ms
V_{DD} Fall Time	t_5	—	—	500	ms
V_P Fall Time	t_6	0.01	—	500	ms
$V_{12} - V_{DD}$ Delay Time	t_7	0	—	—	ms
$V_{DD} - V_P$ Delay Time	t_8	—	—	50	ms

see Fig. 4

Recommended Operating Conditions, continued

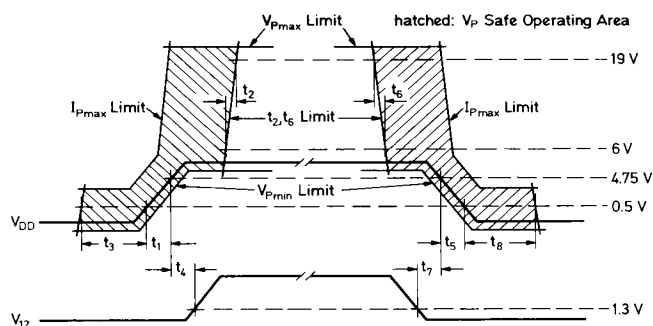


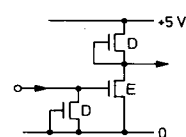
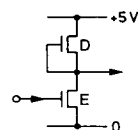
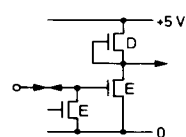
Fig. 4: Power on/off timing

Characteristics at $V_{DD} = 5\text{ V}$, $V_P = 20\text{ V}$, $f_{13} = 1\text{ kHz}$, $T_A = 25\text{ }^{\circ}\text{C}$

	Symbol	Min.	Typ.	Max.	Unit
Current Consumption Pin 14	I_{DD}	10	—	40	mA
Pin 3, Programming Mode	I_P	0.3	—	2	mA
Non-Programming Mode	I_P	10	—	40	μA
Input Leakage Current Pins 8, 9, 12 and 13 at $V_{IH} = 5\text{ V}$	$-I_{IH}$	—	—	10	μA
IM Bus High Level Output Leakage Current at $V_{OH} = 5\text{ V}$, Pin 10	$-I_{OH}$	—	—	10	μA
IM Bus Low Level Output Voltage at $I_{OL} = 3\text{ mA}$, Pin 10	V_{OL}	—	—	0.4	V
Input Internal Pull-Down Current at $V_{IH} = 5\text{ V}$, Pins 1 and 6	I_{IH}	35	—	260	μA
Erase or Write Time at $f_{13} = 1\text{ kHz}$	t_P	15.9	—	17.1	ms

4. Inner Configuration of the Connection Pins

The following figures schematically show the circuitry at the various pins. The integrated protection structures are not shown. The letter "E" means enhancement, the letter "D" depletion.

Fig. 5:
Pins 1 and 6, InputsFig. 6:
Pins 8, 9, 12 and 13, InputsFig. 7:
Pin 10, Input/Output

5. Description of the Connections and the Signals

Pin 1 – Option Input

Fig. 5 shows the internal configuration of this input. With Pin 1 at ground potential (low) or floating, the MDA 2062 reacts upon the IM bus addresses 128, 129 and 131. With pin 1 continuously at V_{DD} potential (high), the MDA 2062 reacts upon this IM bus addresses 132, 133 and 135 (see Fig. 8). In this way, parallel operation of two MDA 2062 is permitted, to obtain 2048 bits of non-volatile storage directly accessible via the IM bus. Pin 1 is internally tied to ground via a transistor equivalent to a 40 k Ω resistor.

Pins 2, 4, 5 and 11 – NC

These pins are not connected internally.

Pin 3 – Programming Voltage V_P

A programming voltage of + 20 V ($\pm 5\%$) is required. The current consumption during programming is approximately 1 mA. During non-programming operations, pin 3 may be held at any level between ($V_{DD} - 0.7$ V) and + 21 V. It may also be left floating. The MDA 2062 EEPROM **must not** be inserted or removed from a socket with $V_P \geq 6$ V. During power on/off sequences, current from the V_P supply should be limited to $I_{P\max} = 5$ mA.

Pin 6 – Safe Input \bar{S}

Fig. 5 shows the internal configuration of this input. Normally, with pin 6 at ground potential (low), one portion of the programming matrix is protected so that this part of the memory cannot be reprogrammed inadvertently. Only when pin 6 receives high potential continuously, the protected portion of the memory matrix can be programmed. Pin 6 is internally tied to ground via a transistor equivalent to a 40 k Ω resistor.

Pin 7 – Ground, 0

This pin must be connected to the negative of the supplies.

Pins 8 to 10 – IM Bus Connections

These pins serve to connect the MDA 2062 EEPROM to the IM bus (see section 7.), via which it communicates with the CCU 2030/2050/2070 or MAA 4030 series μ C or the SAA 1280/SAA 1290/SAA 1293. Pins 8 (IM Bus Clock Input) and 9 (IM Bus Ident Input) are inputs as shown in Fig. 6 and pin 10 (IM Bus Data) is an input/output as shown in Fig. 7. The signal diagram for the IM bus is illustrated in Figs. 8 and 11. The required addresses which the MDA 2062 EEPROM receives from the microcomputer, are also shown in Fig. 8.

Pin 12 – $\overline{\text{Reset}}$ Input

This input has a configuration as shown in Fig. 6. Via this input, the MDA 2062, together with the other circuits belonging to the system, receives the $\overline{\text{Reset}}$ signal which is derived from V_{DD} via an external RC circuit. A low level is required during power-up and power-down procedures. Low level at pin 12 (max. 1.3 V) cancels a programming procedure and an IM bus operation in progress. The memory address register is not, the repair register is erased. During operation, pin 12 requires high level (min. 2.4 V).

Pin 13 – Memory Clock Input

Via this input (Fig. 6) the MDA 2062 receives a 1 kHz clock signal from pin 3 of the CCU 2030, CCU 2050, CCU 2070 or MAA 4030 microcomputer or the SAA 1280/SAA 1290/SAA 1293.

Pin 14 – Supply Voltage V_{DD}

The supply voltage required is + 5 V ($\pm 5\%$), and the current consumption in active operation is approx. 30 mA.

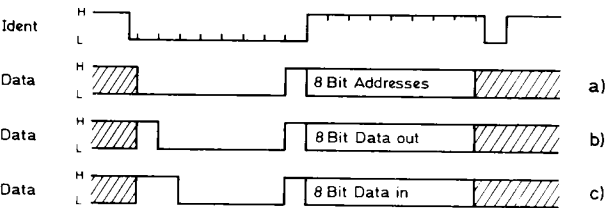


Fig. 8: Signal diagram for the IM bus

	Pin 1 low	Pin 1 high	
a) enter memory			
address:	128	132	followed by address
b) reading:	129	133	followed by data out
c) programming:	131	135	followed by data in

6. Test Functions

This description of the test byte is not part of the specification. It contains no information necessary for normal (intended) use of the MDA 2062 memory. It is only intended as a description of the various functions of the test byte that are designed for factory use, but it does not specify such properties. The description is subject to change.

Address location 4 contains a test byte which governs test mode operation of the MDA 2062. The test byte is set by performing the IM bus operation for entering address 4, followed by an IM bus programming operation with the desired test data word. The test byte is valid during all following IM bus operations until changed or set to 0 by a $\overline{\text{Reset}} = \text{L}$ signal. The test byte shall not be changed during the busy time of a programming operation. Fig. 9 shows the bit arrangement of the test byte. Set bit 5 for activation of the test byte!

Block Programming

Three block program modes can be activated by the test byte, in conjunction with the memory address loaded into the memory address register:

	memory address
	7 6 5 4 3 2 1 0
1) all bytes are selected (including 8 bytes in redundant rows):	1 x x x x 0 x (e. g. 128)
2) all even-numbered bytes are selected (redundant bytes are not predeter- mined, they have to be defined as even bytes):	1 x x x x 1 0 (e. g. 130)
3) all odd-numbered bytes are selected (redundant bytes are not predeter- mined):	1 x x x x 1 1 (e. g. 131)

Block programming enable	Read reference shift -0.3 V	Test Byte enable	Read reference shift -0.6 V	Ramp disable	Read reference shift $+0.3\text{ V}$	Redundancy disable	Read reference shift $+0.6\text{ V}$
7	6	5	4	3	2	1	0

Fig. 9: Functions of the 8 bits in the test byte

Thus, programming all selected bytes with the same desired data is done within one programming sequence. The complete sequence is:

Enter Address 4
 Program Test byte (e. g. 160)
 Enter Address 128, 130 or 131
 Program Data

A checkerboard pattern is programmed with two programming operations after loading the test byte:

Enter Address 130
 Program Data 85
 Enter Address 131
 Program Data 170

Read Reference Shifting

During read operations the memory cell threshold voltage is compared with a reference voltage. The comparator output then produces the logic one level for a cell threshold higher than the reference and the logic zero level for a cell threshold lower than the reference.

The test byte provides means to shift the reference voltage in positive or negative direction in three steps: $\pm 0.3\text{ V}$, $\pm 0.6\text{ V}$ and $\pm 0.9\text{ V}$.

During a read operation a positive-shifted reference voltage establishes a margin test for logic ones, whereas a negative-shifted reference does so for logic zeroes. This margin test is performed digitally by IM bus operations only, without the need to switch analog power supplies.

	7	6	5	4	3	2	1	0
+ 0.9 V:	x	0	1	0	x	1	x	1
+ 0.6 V:	x	0	1	0	x	0	x	1
+ 0.3 V:	x	0	1	0	x	1	x	0
- 0.3 V:	x	1	1	0	x	0	x	0
- 0.6 V:	x	0	1	1	x	0	x	0
- 0.9 V:	x	1	1	1	x	0	x	0

Redundancy Disable

With bit one of the test byte set, the redundant rows can be accessed neither during byte program operations nor during any read operation, even if the redundancy registers are properly loaded. This test byte function has no effect on block programming operations.

Ramp Disable

The MDA 2062 contains circuitry to shape the internal program supply voltage to be a ramp function during programming operations. This feature is considered to be essential to a high erase/write endurance of the memory cells.

Bit 3 of the test byte disables this ramp function so that the internal program supply, according to the timing diagram Fig. 10, is immediately disconnected from the V_{DD} supply and connected to the V_P supply at the 4th falling edge of the 1 kHz memory clock, and is immediately disconnected from the V_P supply and re-connected to the V_{DD} supply at the 14th falling edge of the 1 kHz clock after the last rising Ident signal edge of the IM bus operation starting the program cycle. By this feature other than the built-in ramp function (approx. $100\text{ }\mu\text{s/V}$) can be applied via the V_P supply pin.

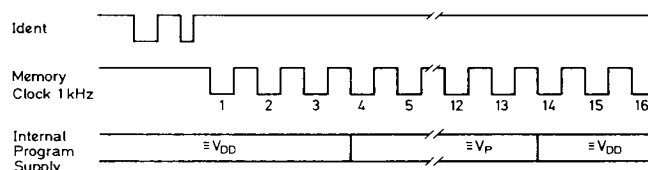


Fig. 10: Ramp disable timing diagram

7. Description of the IM Bus

The INTERMETALL Bus (IM Bus for short) has been designed to control the DIGIT 2000 ICs by the CCU Central Control Unit. Via this bus the CCU can write data to the ICs or read data from them. This means the CCU acts as a master whereas all controlled ICs are slaves.

The IM Bus consists of three lines for the signals Ident (ID), Clock (CL) and Data (D). The clock frequency range is 50 Hz to 170 kHz. Ident and clock are unidirectional from the CCU to the slave ICs, Data is bidirectional. Bidirectionality is achieved by using open-drain outputs with On-resistances of $150\text{ }\Omega$ maximum. The $2.5\text{ k}\Omega$ pull-up resistor common to all outputs is incorporated in the CCU.

The timing of a complete IM Bus transaction is shown in Fig. 11 and Table 1. In the non-operative state the signals of all three bus lines are High. To start a transaction the CCU sets the ID signal to Low level, indicating an address transmission, and sets the CL signal to Low level as well to switch the first bit on the Data line. Thereafter eight ad-

dress bits are transmitted beginning with the LSB. Data takeover in the slave ICs occurs at the positive edge of the clock signal. At the end of the address byte the ID signal goes High, initiating the address comparison in the slave circuits. In the addressed slave the IM bus interface switches over to Data read or write, because these functions are correlated to the address.

Also controlled by the address the CCU now transmits eight or sixteen clock pulses, and accordingly one or two

bytes of data are written into the addressed IC or read out from it, beginning with the LSB.

The completion of the bus transaction is signalled by a short Low-state pulse of the ID signal. This initiates the storing of the transferred data.

It is permissible to interrupt a bus transaction for up to 10 ms.

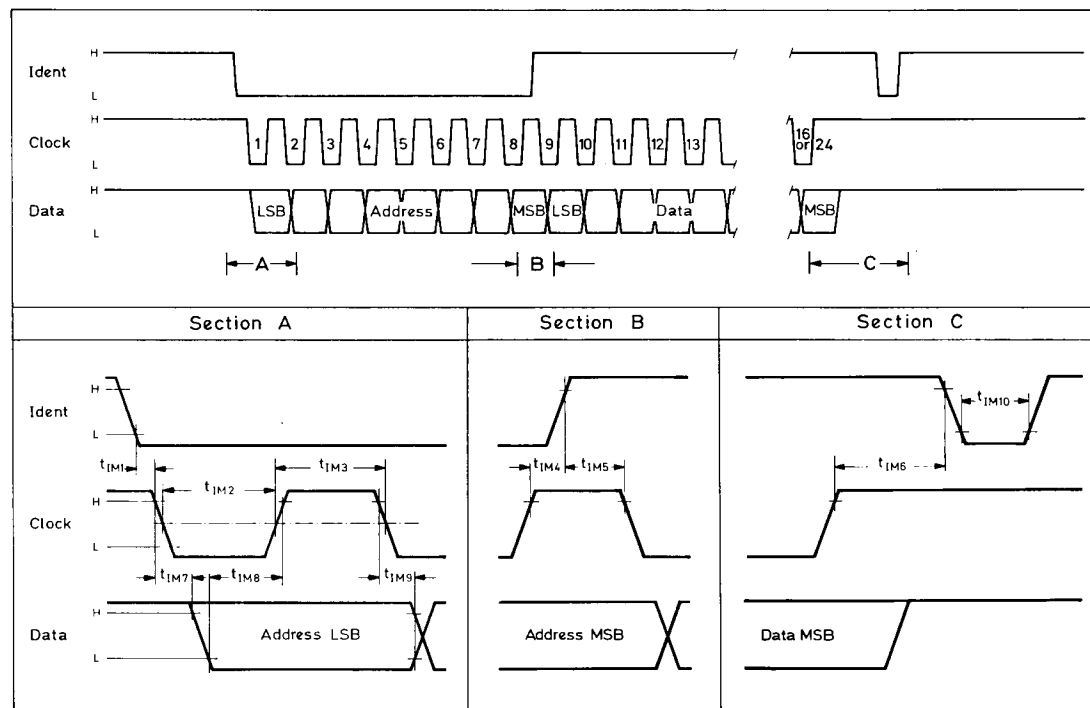


Fig. 11: Waveforms of the IM bus signals

Table 1: Timing of the IM bus signals

Time	t_{IM1}	t_{IM2}	t_{IM3}	t_{IM4}	t_{IM5}	t_{IM6}	t_{IM7}	t_{IM8}	t_{IM9}	t_{IM10}
Min. μs	0	3.0	3.0	0	1.5	6.0	0	0	0	3.0

Production and Marketing Centers:

U.S.A.

ITT COMPONENTS
5 Jenner Street
Irvine, California 92718
(714) 727-3001

W. Germany
INTERMETALL GmbH
P.O. Box 840
D-7800 Freiburg
Tel. (0761) 517-0
Telex 772 715

Japan
ITT Semiconductors FEL
P.O. Box 21
Shinjuku-ku
Tokyo 160-91
Tel. (03) 347 88 81-5
Telex 22 858

Reprinting is generally permitted, indicating the source. However, our consent must be obtained in all cases. Information furnished by ITT is believed to be accurate and reliable. However, no responsibility is assumed by ITT for its use; nor for any infringements of patents or other rights of third parties which may result from its use. No license is granted by implication or otherwise under any patent or patent rights of ITT. The information and suggestions are given without obligation and cannot give rise to any liability; they do not indicate the availability of the components mentioned. Delivery of development samples does not imply any obligation of ITT to supply larger amounts of such units to a fixed term. To this effect, only written confirmation of orders will be binding.

Printed in W. Germany · Imprimé dans la République Fédérale d'Allemagne by Rombach: Druckhaus KG, Freiburg i. Br.

Edition 1987/3 · Order No. 6251-295-1E

MAY 1 8 1993